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R.-M.; Feiste, U.; Xu, L.; Lucero, A.J.; Foursa, D.G.; Bergano, N.S.;*
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hybrid Raman/EDFAs with 80 nm of continuous bandwidth
*Foursa, D.G.; Davidson, C.R.; Nissov, M.; Mills, M.A.; Xu, L.; Cai, J.X.; Pilipet
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